

JAPIO (Japan Patent Information Organization database)



Subject Coverage	<ul style="list-style-type: none">All areas of science and technology, i.e., all classes of the International Patent Classification										
File Type	Bibliographic										
Features	<table><tr><td>Thesaurus</td><td>International Patent Classification (/IPC)</td></tr><tr><td>Alerts (SDIs)</td><td>Not available</td></tr><tr><td>CAS Registry Number® Identifiers</td><td><input type="checkbox"/> Page Images <input type="checkbox"/></td></tr><tr><td>Keep & Share</td><td><input checked="" type="checkbox"/> SLART <input checked="" type="checkbox"/></td></tr><tr><td>Learning Database</td><td><input type="checkbox"/> Structures <input type="checkbox"/></td></tr></table>	Thesaurus	International Patent Classification (/IPC)	Alerts (SDIs)	Not available	CAS Registry Number® Identifiers	<input type="checkbox"/> Page Images <input type="checkbox"/>	Keep & Share	<input checked="" type="checkbox"/> SLART <input checked="" type="checkbox"/>	Learning Database	<input type="checkbox"/> Structures <input type="checkbox"/>
Thesaurus	International Patent Classification (/IPC)										
Alerts (SDIs)	Not available										
CAS Registry Number® Identifiers	<input type="checkbox"/> Page Images <input type="checkbox"/>										
Keep & Share	<input checked="" type="checkbox"/> SLART <input checked="" type="checkbox"/>										
Learning Database	<input type="checkbox"/> Structures <input type="checkbox"/>										
Record Content	<ul style="list-style-type: none">Assignee data, publication information, JPC codes, as well as titles and abstracts in English (Abstracts are available for all applications originating in Japan, and also for many foreign applications).Images of front page drawings are also included, when available.The file is enhanced with bibliographic data from INPADOC.										
File Size	<ul style="list-style-type: none">11.063.060 records and 8.084.132 images (02/2013)										
Coverage	<ul style="list-style-type: none">October 1976-February 2013 (PAJ data)April 1973-1997 (INPADOC data 1.620,000 records)										
Updates	Closed file										
Language	English										
Database Producer	Japanese Patent Office 3-4-3, Kasumigaseki Chiyoda-ku, Tokyo 100-8915 Japan Phone; +81 3 3581-0762 Copyright Holder										
Database Supplier	FIZ Karlsruhe STN Europe P.O. Box 2465 76012 Karlsruhe Germany Phone: +49-7247-808-555 Fax: +49-7247-808-259 Email: helpdesk@fiz-karlsruhe.de										

- Sources**
- Patent Abstracts of Japan (CD-ROM), Unexamined Patent Applications (Kokai Tokkyo Koho)
 - INPADOC database
-

- User Aids**
- Online Helps (HELP DIRECTORY lists all help messages available)
 - STNGUIDE
-

- Cluster**
- ALLBIB
 - AUTHORS
 - CORPSOURCE
 - HPATENTS
 - PATENTS

STN Database Cluster information:

<http://www.stn-international.com/en/training-center/documentation/current-awareness-alerts-sdi-user-guide>

Search and Display Field Codes

Fields that allow left truncation are indicated by an asterisk (*).

General Search Fields

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index* (contains single words from title (TI), and abstract (AB) fields)	None or /BI	S ELECTRONIC PUBLISHING S VIDEO(1W)RECORDER(L)ELECTRONICS S L1 AND ?SYSTEM?	TI, AB
Accession Number	/AN	S 2002-064999/AN	AN
Application Country (WIPO code and text)	/AC	S JP/AC AND L7	AI
Application Date (1)	/AD	S 2 OCT 1998/AD	AI
Application Number (2)	/AP	S 1991JP----0052634/AP S JP1991----52634/AP	AI
Application Year (1)	/AY	S 1998/AY	AI
Document Type (code and text)	/DT (or /TC)	S L7 AND P/DT	DT
Entry Date (1)	/ED	S ED>=AUG 2002	ED
Field Availability	/FA	S L1 AND GI/FA S L1 NOT NOAB/FA	FA
Graphic Image Size (1)	/GIS	S GIS > 32000	GIS
Graphic Image Type	/GIT	S TIF/GIT	GIT
International Patent Classification (contains ICM and ICS)	/IC	S G06F/IC S G06F015/IC S G06F015-40/IC	IC
Inventor	/IN (or /AU)	S HONMA HIDEO/IN	IN
IPC (contains ICM, ICS, ICA, ICI, IPCI) (3)	/IPC	S A01B0001-02/IPC S H05B0006-36+NT/IPC S H05B0006-36-H05B0006-44/IPC	ICA, ICI, ICM, ICS, IPCI
IPC, Action Date (1)	/IPC.ACD	S IPC.ACD=JAN 2006	IPC.TAB
IPC, Additional (Supplementary)	/ICA	S G01B003/ICA	ICA
IPC, Index (Complementary)	/ICI	S B08B101:08/ICI	ICI
IPC, Initial	/IPCI	S B21B0001/IPCI	IPCI
IPC, Keyword Terms	/IPC.KW	S CORE/IPC.KW	IPC.TAB
IPC, Main	/ICM	S H02M/ICM S H02M003/ICM S H02M003-155/ICM	ICM
IPC, Secondary	/ICS	S G11B027-00/ICS	ICS
IPC, Version (1)	/IPC.VER	S 200601/IPC.VER	IPC.TAB
Language (ISO code and text)	/LA	S EN/LA S ENGLISH/LA	LA
Main Group of IPC Version 1-7 Range Searchable (1)	/MGR	S C09K/ICM(S)18-20/MGR	not displayed
Patent Assignee (4)	/PA (or /CS)	S DAINIPPON PRINT?/PA	PA
Patent Country (WIPO code and text)	/PC	S L7 AND JP/PC	PI
Patent Kind Code	/PK	S ENERGY EXCHANG? AND JPA/PK	PI
Patent Number (2)	/PN	S JP06096131/PN	PI
Patent Number Group (2)	/PATS	S JP06096131/PATS	PI
Priority Country (WIPO code and text)	/PRC	S AU/PRC S AUSTRALIA/PRC	PRAI
Priority Date (1)	/PRD	S 29 MAY 1992/PRD	PRAI
Priority Date, First (1)	/PRDF	S 29 MAY 1992/PRDF	PRAI
Priority Number (2)	/PRN	S FR1992-13039/PRN S 1992FR-0013039/PRN	PRAI
Priority Year (1)	/PRY	S 1989/PRY	PRAI
Priority Year, First (1)	/PRYF	S 1989/PRYF	PRAI

Search and Display Field Codes (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Publication Date (1)	/PD	S 19990629/PD	PI
Publication Year (1)	/PY	S 1992/PY	PI
Source (contains abstract journal and volume)	/SO	S VOL 2001/SO	SO
Subgroup of IPC Version 1-7 Range-Searchable (1)	/SGR	S C09K011/ICM(S)8000-20000/SGR	not displayed
Title	/TI	S DC-DC CONVERTER#/TI	TI
Update Date (1)	/UP	UP=APR 2004	UP

(1) Numeric search field that may be searched using numeric operators or ranges.

(2) Either STN format or Derwent format may be used.

(3) An online thesaurus is available in this field.

(4) Search with implied (S) proximity is available in this field.

Super Search Fields (1)

Search Field Name	Search Code	Fields Searched	Search Examples	Display Codes
Application Number Group	/APPS	/AP, /PRN	S 1991JP-0052634/APPS S JP1991-52634/APPS	AI, PRAI

(1) Enter a super search code to execute a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multifile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual field codes instead.

International Patent Classification (/IPC) Thesaurus

The classifications, validity and catchwords for the main headings and subheadings from the current (8th) edition of the WIPO International Patent Classification (IPC) manual are available. The classifications from the previous editions (1-7) are also available as separate thesauri. To EXPAND and SEARCH in the thesauri for editions 1-7, use the field code followed by the edition number, e.g., /IPC2, for the 2nd edition. Catchwords are included only in the thesauri for the 8th, 7th, 6th, and 5th editions.

Code	Content	Examples
ADVANCED (ADV)	Advanced Codes for the Core Level IPC Code	E A61K0006-02+ADVANCED/IPC
ALL	All Associated Terms (BT, SELF, NT, RT)	E C01C003-00+ALL/IPC
BRO (MAN)	Complete Class	E C01C+BRO/IPC
BT	Broader Term (BT, SELF)	E C01F001-00+BT/IPC
CORE (COR)	Core Codes for the Advanced Level IPC Code	E G08C0019-22+CORE/IPC
ED	Complete title of the SELF term and IPC manual edition	E C01F001-00+ED/IPC
HIE	Hierarchy Term (Broader and Narrower Term) (BT, SELF, NT)	E C011003-00+HIE/IPC
INDEX	Complete title of the SELF term	E C01F001-00+INDEX/IPC
KT	Keyword Term (catchwords) (SELF, KT)	E CYANOGEN+KT/IPC
NEXT	Next Classification	E C01C001-00+NEXT5/IPC
NT	Narrower Terms (SELF, NT)	E C01C+NT/IPC
PREV	Previous Classification	E C01C001-12+PREV10/IPC
RT (SIB)	Related Terms (SELF, RT)	E C01C003-20+RT/IPC
TI	Complete Title of the SELF Term and Broader Terms (BT, SELF)	E C01F001-00+TI/IPC

DISPLAY and PRINT Formats

Any combination of formats may be used to display or print answers. Multiple codes must be separated by spaces or commas, e.g., D L1 1-5 TI AU. The fields are displayed or printed in the order requested.

Hit-term highlighting is available for all fields. Highlighting must be ON during SEARCH to use the HIT, KWIC, and OCC formats.

Format	Content	Examples
AB AI (AP) (1) AN DT (TC) ED (2) FA GI GIS (2) GIT (2) IC ICA ICI ICM ICS IN (AU) IPCI PA (CS) PI (PATS, PN) (1) PRAI (PRN) (1) SO TI UP (2)	Abstract Application Information Accession Number Document Type Entry Date Field Availability Graphic Image Graphic Image Size Graphic Image Type IPC (format contains ICM, ICS) IPC, Additional (Supplementary) IPC, Index (Complementary) IPC, Main IPC, Secondary Inventor IPC, Initial Patent Assignee Patent Information Priority Information Source Title Update Date	D TI AB 1-5 D AI D L3 AN D DT LA D ED D FA D GI D GIS D GIT D IC D ICM D ICD D IN D IPCI D PA D PI D PRAI D TI
ABS ALL (1) ALLG (1) DALL (1) IALL (1) IALLG (1) APPS (1) BIB (1) BIBG (1) IBIB (1) IPC (IND) IPC.TAB SCAN (3) STD (1) STDG (1) ISTD (1) TRIAL (TRI, SAMPLE, SAM)	AN, AB AN, TI, IN, PA, PI, AI, PRAI, SO, IPC, AB ALL plus Graphic Image ALL, delimited for post-processing ALL, indented with text labels IALL plus Graphic Image AI, PRAI AN, TI, IN, PA, PI, AI, PRAI, SO BIB plus Graphic Image BIB, indented with text labels ICA, ICI, IPC (ICM, ICS, IPCI) IPC, IPC.KW, IPC.ACD, IPC.VER in Tabular Format TI (random display without answer numbers) AN, TI, IN, PA, PI, AI, PRAI, SO, IPC (STD is default) STD plus Graphic Image STD, indented with text labels TI, FA, DETN, CLMN	D TI PA ABS D ALL D DALL D IALL 1-3 D BIB D IPC PA D SCAN
HIT KWIC OCC	Hit term(s) and field(s) Up to 50 words before and after hit term(s) (KeyWord-In-Context) Number of occurrences of hit term(s) and field(s) in which they occur	D OCC 1-6

(1) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.

(2) Custom display only.

(3) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.

SELECT, ANALYZE, and SORT Fields

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Abstract	AB	Y (2)	N
Accession Number	AN	Y	N
Application Country	AC	Y	Y
Application Date	AD	Y	Y
Application Information	AI (AP)	Y	Y
Application Number	AP	Y	Y
Application Number Group	APPS	Y	N
Document Type	DT (TC)	Y (3)	N
Entry Date	ED	Y	Y
Field Availability	FA	Y (3)	N
Graphic Image Size	GIS	Y	Y
Graphic Image Type	GIT	Y	Y
International Patent Classification	IC	Y	Y
Inventor	IN (AU)	Y	Y
IPC (ICM, ICS, ICA, ICI, IPCI, IPCR)	IPC	Y	N
IPC, Additional (Supplementary)	ICA	Y	Y
IPC, Advanced Level Symbols	IPC.A	Y (4)	N
IPC, Advanced Level Symbols for Invention	IPC.AI	Y (4)	N
IPC, Core Level Symbols	IPC.C	Y (4)	N
IPC, Core Level Symbols for Invention	IPC.CI	Y (4)	N
IPC, Index (Complementary)	ICI	Y	Y
IPC, Initial	IPCI	Y (4)	N
IPC, Main	ICM	Y	Y
IPC, Secondary	ICS	Y	Y
Language	LA	Y (3)	N
Patent Assignee	PA (CS)	Y	Y
Patent Country	PC	Y	Y
Patent Information	PI (PN, PATS)	Y	Y
Patent Kind Code	PK	Y	Y
Patent Number	PN	Y	Y
Patent Number Group	PATS	Y	N
Pre-IPC8 Symbols from the ICM and first IPC8 values from 2006 onwards	IPC.F	Y (4)	N
Priority Country	PRC	Y	Y
Priority Date	PRD	Y	Y
Priority Date, First	PRDF	Y	Y
Priority Information	PRAI (PRN)	Y	Y
Priority Information, Original	PRAI	Y	Y
Priority Number	PRN	Y	Y
Priority Year	PRY	Y	Y
Priority Year, First	PRYF	Y	Y
Publication Date	PD	Y	Y
Publication Year	PY	Y	Y
Source	SO	Y	N

SELECT, ANALYZE, and SORT Fields (cont'd)

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Subclass	SCL	Y (5)	N
Subclass Additional	SCLA	Y (6)	N
Subclass Group	SCG	Y (5)	N
Subclass Group Additional	SCGA	Y (6)	N
Subclass Group Main	SCGM	Y (5)	N
Subclass Group Secondary	SCGS	Y (7)	N
Subclass Main	SCLM	Y (5)	N
Subclass Secondary	SCLS	Y (7)	N
Title	TI	Y (default)	Y
Update Date	UP	Y	Y

- (1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.
(2) Appends /BI to the terms created by SELECT.
(3) SELECT HIT or ANALYZE HIT are not valid with this field.
(4) Appends /IPC to the terms created by SELECT.
(5) Appends /ICM to the terms created by SELECT.
(6) Appends /ICA to the terms created by SELECT.
(7) Appends /ICS to the terms created by SELECT.

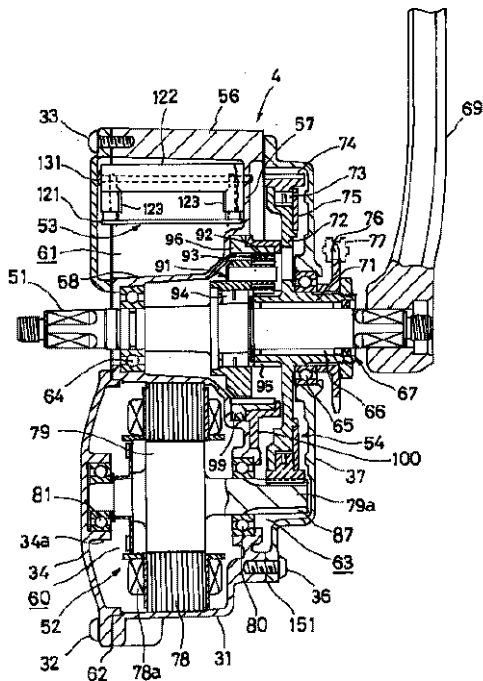
Sample Records**DISPLAY IALLG (STN format)**

ACCESSION NUMBER: 2001-088768 JAPIO
TITLE: POWER UNIT FOR ELECTRIC MOTOR ASSIST BICYCLE
INVENTOR: NAKAYAMA HIRONORI
PATENT ASSIGNEE(S): YAMAHA MOTOR CO LTD
PATENT INFORMATION:

PATENT NO	KIND	DATE	ERA	MAIN IPC
JP 2001088768	A	20010403	Heisei	B62M023-02

APPLICATION INFORMATION

STN FORMAT: JP 1999-266739 19990921
ORIGINAL: JP11266739 Heisei
PRIORITY APPLN. INFO.: JP 1999-266739 19990921
SOURCE: PATENT ABSTRACTS OF JAPAN (CD-ROM), Unexamined Applications, Vol. 2001
INT. PATENT CLASSIF.:
MAIN: B62M023-02



ABSTRACT:

PROBLEM TO BE SOLVED: To provide a power unit for an electric motor assist bicycle capable of improving an assembling property and a heat insulating property of a motor and a controller and capable of reducing cost.
 SOLUTION: A motor 52 is arranged to the rear of a car body from a pedal crankshaft 51 in a state where the axial direction comes to be in parallel with the pedal crankshaft 51. A controller 53 is arranged in front of the car body. The motor 52 and the controller 53 are structured to assemble on a housing 31 from the left side of the car body. A gear type power transmission device 54 to transmit rotation of the motor 52 and the pedal crankshaft 51 to a resultant force shaft 67 is structured to assemble on the housing 31 from the right side of the bicycle body. COPYRIGHT: (C)2001, JPO

DISPLAY ALL (STN Format)

AN 2006-025600 JAPIO
 TI ELECTRIC POWER REJECTION SYSTEM
 IN UMEKAGE YASUHIRO; NAKANE SHINICHI; KIMATA KUNIO; UEDA YASUKIYO; UEDA KOKICHI
 PA MATSUSHITA ELECTRIC IND CO LTD
 PI JP 2006025600 A 20060126 Heisei
 AI JP 2005-271641 (JP2005271641 Heisei) 20050920
 PRAI JP 2005-271641 20050920
 SO PATENT ABSTRACTS OF JAPAN (CD-ROM), Unexamined Applications, Vol. 2006
 IPCI H02H0005-00 [I,A]; H02J0013-00 [I,A];
 H02H0005-00 [I,C*]; H02J0013-00 [I,C*]
 AB PROBLEM TO BE SOLVED: To reject the supply of electric power when an earthquake occurs, with regard to an electric power rejection system.
 SOLUTION: The electric power rejection system is constituted of a gas flow measurement means 7 for measuring a gas flow, a seismoscope 8 for detecting vibration, an abnormality decision means 9 for deciding an abnormality, when the seismoscope 8 detects prescribed vibration, a transmission means 10 for transmitting an abnormality decision signal from the abnormality decision means 9, a gas meter 12 provided with a gas cut-off valve 11

cutting off a gas flow by the abnormality decision signal, a receiving means 13 for receiving the abnormality decision signal from the transmission means 10 provided in the gas meter 12, an electric power interruption switch 14 for interrupting the supply of electric power, and an electric breaker 16 provided with a control means 15 for disconnecting the electric power interruption switch 14 by the abnormality decision signal received by the receiving means 13, the system is constituted so as to shut off the supply of the electric power, after the supply of the gas is interrupted when the abnormality is decided. COPYRIGHT:
(C)2006,JPO&NCIPI

DISPLAY STD (Derwent Format)

AN 2006-025591 JAPIO
 TI VEHICULAR POWER SUPPLY DEVICE
 IN NAKAZAWA YOSUKE; MOCHIKAWA HIROSHI; KIRA HIROTADA; ISHIKAWA TOMOAKI; HENMI TAKUMA
 PA TOSHIBA CORP
 PI JP--2006025591 A 20060126 Heisei
 AI 2005JP-0122787 (JP2005122787 Heisei) 20050420
 PRAI 2004JP-0169330 20040608
 SO PATENT ABSTRACTS OF JAPAN (CD-ROM), Unexamined Applications, Vol. 2006
 IPCI H02M-0003-28 [I,A]; B60L-0001-00 [I,A]; H02M-0007-48 [I,A];
 H02-M0003-24 [I,C*]; B60L-0001-00 [I,C*]; H02M-0007-48 [I,C*]

DISPLAY IPC.TAB

IPC	CODE	VERSION	POS	INV	LEVEL	CC	ASSIGNMENT	DATE	STAT
IPCI	H02M0003-28	(200601)	F	I	Advanced	JP	Human	20051222	O
	B60L0001-00	(200601)	L	I	Advanced	JP	Human	20051222	O
	H02M0007-48	(200601)	L	I	Advanced	JP	Human	20051222	O
	H02M0003-24	(2006)	L	I	Core*	RC	Machine	20051222	O
	B60L0001-00	(2006)	L	I	Core*	RC	Machine	20051222	O
	H02M0007-48	(2006)	L	I	Core*	RC	Machine	20051222	O

In North America

CAS
 STN North America
 P.O. Box 3012
 Columbus, Ohio 43210-0012 U.S.A.

CAS Customer Center:
 Phone: 800-753-4227 (North America)
 614-447-3700 (worldwide)
 Fax: 614-447-3751
 Email: help@cas.org
 Internet: www.cas.org

In Europe

FIZ Karlsruhe
 STN Europe
 P.O. Box 2465
 76012 Karlsruhe
 Germany
 Phone: +49-7247-808-555
 Fax: +49-7247-808-259
 Email: helpdesk@fiz-karlsruhe.de
 Internet: www.stn-international.com

In Japan

JAICI (Japan Association for
 International Chemical Information)
 STN Japan
 Nakai Building
 6-25-4 Honkomagome, Bunkyo-ku
 Tokyo 113-0021, Japan
 Phone: +81-3-5978-3601 (Technical Service)
 +81-3-5978-3621 (Customer Service)
 Fax: +81-3-5978-3600
 Email: support@jaici.or.jp (Technical Service)
 customer@jaici.or.jp (Customer Service)
 Internet: www.jaici.or.jp